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Yi Cai
Haimei Gong
Jean-Pierre Chatard
Editors

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Contents

xi *Conference Committee*
xiii *Symposium Committees*

INFRARED MATERIALS/DEVICES AND THEIR APPLICATION I

- 6835 02 **New architecture for TECless operation of uncooled microbolometers developed at LETI (Invited Paper) [6835-74]**
F. Simoens, CEA-LETI-MINATEC-SLIR (France); M. Tchagaspanian, CEA-LETI-MINATEC-DCIS (France); A. Arnaud, P. Imperinetti, CEA-LETI-MINATEC-SLIR (France); G. Chamming, CEA-LETI-MINATEC-DCIS (France); J. J. Yon, CEA-LETI-MINATEC-SLIR (France); J. L. Tissot, ULIS (France); G. Destefanis, CEA-LETI-MINATEC-SLIR (France)
- 6835 04 **New concept system research and development base on advanced infrared detector [6835-26]**
Q. Ding, H. Liu, Luoyang Institute of Electro-Optical Equipment of AVIC (China)
- 6835 05 **256×1 element linear InGaAs short wavelength near-infrared detector arrays [6835-27]**
X. Li, H. Tang, G. Fan, D. Liu, X. Shao, Shanghai Institute of Technical Physics (China); Y. Zhang, Shanghai Institute of Microsystem and Information Technology (China); H. Zhang, X. Chen, S. Zhu, H. Gong, J. Fang, Shanghai Institute of Technical Physics (China)
- 6835 06 **Performance analysis of 256 element linear 2.4μm InGaAs photovoltaic detector arrays [6835-29]**
K. Zhang, H. Tang, X. Wu, Shanghai Institute of Technical Physics (China) and Graduate School of the Chinese Academy of Sciences (China); X. Li, Shanghai Institute of Technical Physics (China); Y. Zhang, Shanghai Institute of Microsystem and Information Technology (China); H. Gong, Shanghai Institute of Technical Physics (China)

INFRARED MATERIALS/DEVICES AND THEIR APPLICATION III

- 6835 0A **Near-infrared photodetectors based on mercury indium telluride single crystals (Invited Paper) [6835-48]**
X. Zhang, W. Sun, Northwestern Polytechnical Univ. (China) and Luoyang Optoelectronic Institute (China); Z. Lu, L. Zhang, L. Zhao, J. Ding, G. Yan, Luoyang Optoelectronic Institute (China)
- 6835 0B **Performance and reliability characteristic of Stirling cryocoolers [6835-40]**
X. G. Liu, Y. N. Wu, L. He, Shanghai Institute of Technical Physics (China)
- 6835 0C **Spatial light modulator based on sheared polymer network liquid crystal [6835-50]**
Y. Luo, J. Gao, Xi'an Applied Optics Institute (China)
- 6835 0D **Properties of Au/Pt/Ti contact to p-InP by rapid thermal processing [6835-56]**
Y. Lv, Luoyang Optoelectronic Institute (China); H. Tang, B. Han, X. Wu, K. Zhang, X. Li, H. Gong, Shanghai Institute of Technical Physics (China)

- 6835 OE **A novel vibration control system for Stirling cryocoolers** [6835-62]
B. Yang, Y. Wu, Y. Tang, H. Fu, G. Lu, G. Chen, Shanghai Institute of Technical Physics (China)

INFRARED MATERIALS/DEVICES AND THEIR APPLICATION IV

- 6835 OF **Uncooled amorphous silicon 160×120 IRFPA with 25 μm pixel-pitch for large volume applications (Invited Paper)** [6835-105]
M. Vilain, J. L. Tissot, O. Legras, ULIS (France); J. J. Yon, CEA-LETI (France); C. Minassian, B. Fièque, J. M. Chiappa, ULIS (France)
- 6835 OG **Innovative on-chip packaging applied to uncooled IRFPA** [6835-63]
G. Dumont, A. Arnaud, P. Imperinetti, E. Mottin, F. Simoens, C. Vialle, W. Rabaud, G. Grand, N. Baclet, CEA-LETI, MINATEC (France)
- 6835 OH **Design and simulation of a 512×1 readout circuit for focal plane array** [6835-76]
Y. Li, H. Zhu, X. Li, J. Ding, J. Fang, Shanghai Institute of Technical Physics (China)
- 6835 OI **The formation and elimination of inclusions in CdZnTe crystal** [6835-79]
C. Liu, Shanghai Institute of Technical Physics (China)

INFRARED MATERIALS/DEVICES AND THEIR APPLICATION V

- 6835 OJ **Analysis of the thermal stress of IRFPA assembly using FEM** [6835-80]
H. Zhang, H. Lu, Shanghai Institute of Technical Physics (China)
- 6835 OK **The device for observing the solar on moon in multispectrum** [6835-94]
G. Huang, Q. Xiao, C. Zheng, K. Chu, Z. Jin, Beijing Institute of Technology (China)
- 6835 OL **The electronic structure of the PbS(-100) with vacancy defect: first-principles study** [6835-21]
Z.-L. Ding, H.-Z. Xing, Donghua Univ. (China); Y. Huang, X.-S. Chen, Shanghai Institute of Technical Physics (China)
- 6835 OM **Generation of ultrashort mid-infrared pulses by super continuum seeded OPA in a MgO: LiNbO₃ crystal** [6835-83]
Y. Deng, Q. Zhu, X. Zeng, Y. Zhang, X. Wang, F. Wang, X. Huang, X. Xie, Y. Zuo, Research Ctr. of Laser Fusion (China)
- 6835 ON **Progress in cooled IR detectors and new developments** [6835-85]
P. Tribolet, M. Vuillermet, Sofradir (France)

INFRARED IMAGERS/SYSTEMS AND THEIR APPLICATION I

- 6835 OO **Subpixel boundary backward substitution reconstruction algorithm for not uniform microscan to FPA and blind micromotion matching** [6835-13]
Y. Chen, W. Jin, L. Zhao, M. Gao, L. Zhao, Beijing Institute of Technology (China)

- 6835 OP **Analysis of selection of structural element in mathematical morphology with application to infrared point target detection** [6835-16]
J. Guo, Shanghai Institute of Technical Physics (China) and Graduate School of the Chinese Academy of Sciences (China); G. Chen, Shanghai Institute of Technical Physics (China)
- 6835 OQ **Infrared dual spectral imaging system** [6835-17]
H. Wang, A. Geng, C. Yang, Q. Cao, L. Guo, Huazhong Institute of Electro-Optics (China)
- 6835 OR **MODIS-based analysis of snow distribution and change in Emin River basin, Xinjiang, China** [6835-19]
Z. Liu, China Univ. of Mining and Technology (China), Xinjiang Univ. (China), International Ctr. for Desert Affairs (China), and Xinjiang Key Subject of Ecology (China); J. Gao, China Univ. of Mining and Technology (China); H. Pei, S. Fang, Xinjiang Univ. (China)

INFRARED IMAGERS/SYSTEMS AND THEIR APPLICATION II

- 6835 OS **General performance evaluation on thermal imaging systems with the square integral method based on MRTD channel width** [6835-28]
J. Wang, W. Jin, X. Wang, L. Wang, Beijing Institute of Technology (China)
- 6835 OT **Study of dynamic infrared scene projection technology based on digital micro-mirror device (DMD)** [6835-57]
Y. Hu, J. Gao, J. Wang, Y. Zheng, J. Wang, J. Xie, Xi'an Institute of Applied Optics (China)
- 6835 OU **Study on pulsed phase analysis of depth measurement for infrared thermal wave nondestructive evaluation** [6835-69]
Y. Li, Y. Zhao, Beijing Institute of Technology (China); L. Feng, C. Zhang, Capital Normal Univ. (China)

INFRARED IMAGERS/SYSTEMS AND THEIR APPLICATION III

- 6835 OV **Ultrasonic infrared thermal wave nondestructive evaluation for crack detection of several aerospace materials** [6835-71]
W. Xu, J. Shen, C. Zhang, N. Tao, L. Feng, Capital Normal Univ. (China)
- 6835 OX **Optical path layout and moving mirrors of wavemeter based on Michelson interferometer** [6835-89]
L. Wang, Tianjin Univ. of Technology and Education (China); Y. Peng, Beijing Univ. of Technology (China); F. Gao, Y. He, H. Zheng, Tianjin Univ. of Technology and Education (China)
- 6835 IO **MTF testing algorithms for sampled thermal imaging systems** [6835-86]
S. D. Fantone, D. A. Imrie, D. Orband, J. Zhang, Optikos Corp. (USA)

INFRARED IMAGERS/SYSTEMS AND THEIR APPLICATION IV

- 6835 12 **Quantitative analysis of peanut oil content in ternary blended edible oil using near infrared spectroscopy** [6835-101]
H. Chen, F. Liu, Z. Wang, S. Jin, China Jiliang Univ. (China)
- 6835 13 **Calibration research of laser speedometer** [6835-107]
Y. Cui, T. Li, J. Leng, H. Shi, Changcheng Institute of Metrology and Measurement (China)
- 6835 14 **Infrared and visible image fusion algorithm based on Contourlet transform and PCNN** [6835-02]
Y. Lin, L. Song, X. Zhou, Y. Huang, Tianjin Univ. (China)
- 6835 15 **Technology for low-cost PIR security sensors** [6835-97]
K. C. Liddiard, Electro-optic Sensor Design (Australia)

POSTER SESSION

- 6835 16 **High uniformity InGaAs linear mesa-type SWIR focal plane arrays** [6835-03]
H. Tang, X. Wu, K. Zhang, Shanghai Institute of Technical Physics (China) and Graduate School of the Chinese Academy of Sciences (China); L. Ye, N. Wang, X. Li, H. Gong, Shanghai Institute of Technical Physics (China)
- 6835 17 **Iterative infrared image restoration** [6835-06]
T. Si, J. Qiao, Y. Gao, Nanyang Institute of Technology (China) and Nanjing Univ. of Science and Technology (China); B. Chang, Nanjing Univ. of Science and Technology (China)
- 6835 18 **A kind of real-time infrared image enhancement algorithm** [6835-07]
T. Si, Y. Gao, J. Qiao, Nanyang Institute of Technology (China) and Nanjing Univ. of Science and Technology (China); B. Chang, Nanjing Univ. of Science and Technology (China)
- 6835 19 **Growth and characterization of <110> oriented ZnTe single crystal** [6835-08]
R. Wang, W. Fang, P. Zhao, Shanghai Institute of Technical Physics (China); C. Zhang, Nanjing Univ. (China); L. Zhang, J. Ge, S. Yuan, H. Zhang, S. Hu, X. Shen, N. Dai, Shanghai Institute of Technical Physics (China)
- 6835 1A **Application of contourlet transform in infrared image denoising** [6835-10]
Y. Lin, X. Zhou, L. Song, Y. Huang, Tianjin Univ. (China)
- 6835 1B **Study on the thermal field change and affecting factors in urban areas of Hangzhou tourism city** [6835-11]
Q. Cheng, X. Wu, Zhejiang Gongshang Univ. (China)
- 6835 1C **Retrieval of atmospheric water content and transmittance computation of thermal bands based on MODTRAN** [6835-12]
Q. Cheng, X. Wu, Zhejiang Gongshang Univ. (China)
- 6835 1D **Fast curvelet transform based non-uniformity correction for IRFPA** [6835-20]
L. Dong, W. Jin, X. Zhou, Beijing Institute of Technology (China)

- 6835 1E **The distribution of grating-coupled field of quantum well infrared photodetector using FDTD method** [6835-25]
H. Chen, X. Chen, Shanghai Institute of Technical Physics (China); Y. Zeng, Shanghai Institute of Technical Physics (China) and Royal Institute of Technology (Sweden); Z. Li, D. Xiong, W. Lu, Shanghai Institute of Technical Physics (China)
- 6835 1F **An optical model of wide field of view superspectral imager** [6835-33]
Z. He, W. Xu, J. Jia, R. Shu, J. Wang, Shanghai Institute of Technical Physics (China)
- 6835 1G **The research for a system of binocular stereo vision based on the near-infrared imaging characteristics of black-and-white CCD** [6835-34]
P. Zhang, Z. Zhang, Y. Zhang, Academy of Armored Force Engineering (China)
- 6835 1H **Study on the predicted model of crop leaf water status by the NIR band of ground reflectance and spaceborne hyperspectral images** [6835-38]
Q. Jiao, X. Liu, B. Liu, Institute of Remote Sensing Applications (China) and Graduate School of Chinese Academy of Sciences (China); X. Zhang, Graduate School of Chinese Academy of Sciences (China); B. Zhang, Ctr. for Earth Observation and Digital Earth (China)
- 6835 1J **IMMPDA algorithm for infrared target tracking based on multifeature fusion** [6835-43]
J. Zhang, J. Song, Institute of Optics and Electronics (China) and Graduate Univ. of the Chinese Academy of Sciences (China); Q. Wu, Institute of Optics and Electronics (China)
- 6835 1K **New technology of photoelectric reconnaissance based on exploitation of quantum effects** [6835-44]
K. Yang, L. Chen, H. Liu, China Jiliang Univ. (China)
- 6835 1L **Automatic target detection in dual band infrared imagery** [6835-45]
J. Yu, Graduate School of Chinese Academy of Sciences (China) and Shanghai Institute of Technical Physics (China); S. Sun, G. Chen, Shanghai Institute of Technical Physics (China)
- 6835 1M **The side-passivation research on LWIR HgCdTe detector** [6835-46]
Q. Xu, H. Tang, Shanghai Institute of Technical Physics (China) and Graduate School of the Chinese Academy of Sciences (China); H. Gong, Shanghai Institute of Technical Physics (China)
- 6835 1N **Pseudo-color coding method of infrared images based on human vision system** [6835-49]
X. Zhang, T. Bai, H. Li, Beijing Institute of Technology (China)
- 6835 1O **Research of sub-pixel location algorithm based on image correlation** [6835-52]
F. Li, C. Xu, W. Jin, X. Wang, Beijing Institute of Technology (China)
- 6835 1P **A novel infrared image fusion algorithm based on contourlet transform** [6835-54]
Y. Song, K. Gao, G. Ni, Beijing Institute of Technology (China)
- 6835 1Q **Infrared dim small target track predicting using least squares support vector machine** [6835-58]
G. Wang, K. Gao, G. Ni, Beijing Institute of Technology (China)

- 6835 1S **A preliminary study on laser-induced damage in InGaAs material and detectors** [6835-64]
H. Liu, H. Tang, H. Gong, Shanghai Institute of Technical Physics (China)
- 6835 1T **Characterization of multilayered HgCdTe for MW/LW two-color application** [6835-72]
Q. Wei, W. Zhou, Shanghai Institute of Technical Physics (China) and Graduate Univ. of Chinese Academy of Sciences (China); W. Wang, Shanghai Institute of Technical Physics (China); X. Fu, Shanghai Institute of Technical Physics (China) and Graduate Univ. of Chinese Academy of Sciences (China); M. Yu, L. Chen, Y. Wu, L. He, Shanghai Institute of Technical Physics (China)
- 6835 1U **Surface defects induced by impurities in MBE-grown HgCdTe** [6835-73]
X. Fu, Shanghai Institute of Technical Physics (China) and Chinese Academy of Sciences (China); W. Wang, Shanghai Institute of Technical Physics (China); Q. Wei, Shanghai Institute of Technical Physics (China) and Chinese Academy of Sciences (China); J. Wu, L. Chen, Y. Wu, L. He, Shanghai Institute of Technical Physics (China)
- 6835 1V **The research of range-gated laser night vision system on cars** [6835-77]
Z. Zeng, H. Fan, S. Hejun, Institute of Semiconductors (China)
- 6835 1W **Infrared target tracking using multisensor data fusion** [6835-78]
J. Zhang, Y. Lu, H. Zhu, Institute of Optics and Electronics (China) and Graduate Univ. of the Chinese Academy of Sciences (China); Q. Wu, Institute of Optics and Electronics (China)
- 6835 1X **Analysis of thermal stress damage in single-crystal silicon induced by 1064-nm long-pulse laser** [6835-87]
Y. Chen, J. Lu, X. Ni, Nanjing Univ. of Science and Technology (China)
- 6835 1Y **A robust sub-pixel edge detection method of infrared image based on tremor-based retinal receptive field model** [6835-90]
K. Gao, H. Yang, X. Chen, G. Ni, Beijing Institute of Technology (China)
- 6835 1Z **Fast response pyroelectric detector-preamplifier assembled device** [6835-91]
P. Bai, Y. Tai, H. Liu, Kuming North Infrared Science and Technology Co. Ltd. (China)
- 6835 20 **Study of uncooled thermal imaging system with multiple working temperatures** [6835-96]
J. Zhang, T. Si, L. Sun, B. Chang, Y. Qian, Y. Qiu, Nanjing Univ. of Science and Technology (China)
- 6835 21 **Research on 10.6 μm laser beam monitoring in CO₂ laser processing system** [6835-103]
Y. Shi, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); Y. Gao, Changchun Institute of Optics, Fine Mechanics and Physics (China); W. Deng, S. Shao, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China)

- 6835 2Z **Based on Householder transform of the Zernike polynomial wavefront fitting method to solve active optics correction force** [6835-104]
F. Wang, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); F. Yang, Changchun Institute of Optics, Fine Mechanics and Physics (China); X. Wu, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); H. Liu, Changchun Institute of Optics, Fine Mechanics and Physics (China)
- 6835 2E **Design of a recursive filter for infrared image real-time processing** [6835-70]
B. Zhou, Z. Zhou, Y. He, Ordnance Engineering College (China)
- 6835 2H **Application of improved BP neural network in infrared spectroscopy** [6835-92]
M. Gao, H. Zhang, S. Jin, China Jiliang Univ. (China)
- 6835 2L **A novel real-time system for driving an infrared focal plan array based on FPGA** [6835-04]
E. Koohestani, Rayan-Electronic Fardo Co. (Iran); A. Homaei, Rayan-Electronic Fardo Co. (Iran) and Azad Univ. (Iran)

Author Index

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- 1 Infrared Materials/Devices and Their Application I
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- 2 Infrared Materials/Devices and Their Application II
Yi Cai, Kunming Institute of Physics (China)
Jean-Pierre Chatard, ULIS (France)
- 3 Infrared Materials/Devices and Their Application III
Yi Cai, Kunming Institute of Physics (China)
Haimei Gong, Shanghai Institute of Technical Physics (China)
- 4 Infrared Materials/Devices and Their Application IV
Yi Cai, Kunming Institute of Physics (China)
Haimei Gong, Shanghai Institute of Technical Physics (China)
- 5 Infrared Materials/Devices and Their Application V
Yi Cai, Kunming Institute of Physics (China)
- 6 Infrared Imagers/Systems and Their Application I
Yi Cai, Kunming Institute of Physics (China)

- 7 Infrared Imagers/Systems and Their Application II
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- 8 Infrared Imagers/Systems and Their Application III
François Simoens, Commissariat à l'Energie Atomique (France)
Yi Cai, Kunming Institute of Physics (China)
- 9 Infrared Imagers/Systems and Their Application IV
Haimei Gong, Shanghai Institute of Technical Physics (China)
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